FORM PTO-1449

U.S. DEPARTMENT OF **COMMERCE PATENT** AND TRADEMARK OFFICE

List of Information Cited by Applicant Page 1 of 1

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APPLICANT SCHOO, ET AL JAP20 REC'UTUTTO 16 DEC 2005

FILING DATE

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	U.S. PATENT DOCUMENTS						
EXAM. INITIAL		DOCUMENT NUMBER	DATE	NAME	CLS	SUB- CLS	FILE DATE
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/A.H./	AX	Paik et al. (2002) Macromolecules, 35:6782-6791	
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EXAMINER		Anthony Ho/ DATE CONSIDERED	08/11/2007

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.